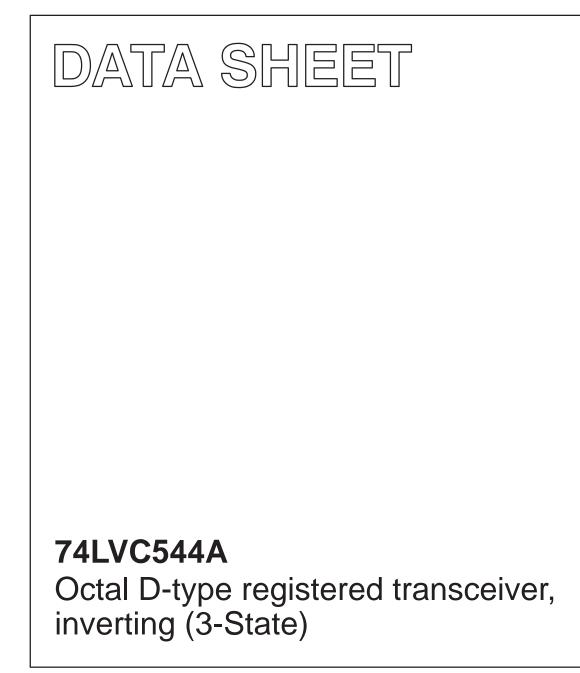
INTEGRATED CIRCUITS



Product specification

1998 Jul 29



PHILIPS

Philips Semiconductors

74LVC544A

FEATURES

- Wide supply voltage range of 1.2V to 3.6V
- In accordance with JEDEC standard no. 8-1A
- CMOS low power consumption
- Direct interface with TTL levels
- Combines 74LVC640 and 74LVC533 type functions in one chip
- Octal transceiver with D-type latch
- Back-to-back registers for storage
- Separate controls for data flow in each direction
- 3-State inverting outputs for bus oriented applications
- 5 Volt tolerant inputs/outputs, for interfacing with 5 Volt logic

DESCRIPTION

The 74LVC544A is a high performance, low-power, low-voltage Si-gate CMOS device and superior to most advanced CMOS compatible TTL families.

Inputs can be driven from either 3.3V or 5.0V devices. In 3-State operation, outputs can handle 5V. This feature allows the use of these devices as translators in a mixed 3.3V/5V environment.

The 74LVC544A is an octal registered inverting transceiver containing two sets of D-type latches for temporary storage of the data flow in either direction. Separate latch enable (LEAB, LEBA) and output enable (OEAB, OEBA) inputs are provided for each register to permit independent control of inputting and outputting in either direction of the data flow.

The '544A' contains eight D-type latches with separate inputs and controls for each set. For data flow from A to B, for example, the A-to-B enable (EAB) input must be LOW in order to enter data from $\overline{A0}$ - $\overline{A7}$ or take data from $\overline{B0}$ - $\overline{B7}$, as indicated in the function table.

With EAB LOW, a LOW signal on the A-to-B latch enable (LEAB) input makes the A-to-B latches transparent; a subsequent LOW-to-HIGH transition of the LEAB signal puts the A data into the latches where it is stored and the B outputs no longer change with the A inputs. With EAB and OEAB both LOW, the 3-State B output buffers are active and display the data present at the outputs of the A latches.

QUICK REFERENCE DATA

$GND = 0V; T_{amb} = 25^{\circ}0$	C; $t_r = t_f \le 2.5 \text{ ns}$			
SYMBOL	PARAMETER	CONDITIONS	TYPICAL	UNIT
t _{PHL} /t _{PLH}	Propagation delay An to Bn	$C_L = 50 pF$ $V_{CC} = 3.3 V$	4	ns
Cl	Input capacitance		5.0	pF
C _{I/O}	Input/output capacitance		10	pF
C _{PD}	Power dissipation capacitance per latch	Notes 1, 2	30	pF

NOTES:

1. C_{PD} is used to determine the dynamic power dissipation (P_{D} in μW)

 $P_{D} = C_{PD} \times V_{CC}^{2} \times f_{i} + \Sigma (C_{L} \times V_{CC}^{2} \times f_{o}) \text{ where:}$ $f_{i} = \text{input frequency in MHz; } C_{L} = \text{output load capacitance in pF;}$

 f_o = output frequency in MHz; V_{CC} = supply voltage in V;

 Σ (C_L × V_{CC}² × f_o) = sum of the outputs.

2. The condition is $V_I = GND$ to V_{CC} .

ORDERING AND PACKAGE INFORMATION

PACKAGES	TEMPERATURE RANGE	OUTSIDE NORTH AMERICA	NORTH AMERICA	PKG. DWG. #
24-Pin Plastic SO	–40°C to +85°C	74LVC544A D	74LVC544A D	SOT137-1
24-Pin Plastic SSOP Type II	-40°C to +85°C	74LVC544A DB	74LVC544A DB	SOT340-1
24-Pin Plastic TSSOP Type I	–40°C to +85°C	74LVC544A PW	7LVC544APW DH	SOT355-1

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PIN DESCRIPTION

PIN NUMBER	SYMBOL	FUNCTION
1	LEBA	'B' to 'A' latch enable input (active LOW)
2	ŌĒBA	'B' to 'A' output enable input (active LOW)
3, 4, 5, 6, 7, 8, 9, 10	A0-A7	'A' data inputs/outputs
11	ĒBA	'B' to 'A' enable input (active LOW)
12	GND	Ground (0V)
22, 21, 20, 19, 18, 17, 16, 15	<u>B0–B7</u>	'B' data inputs/outputs
13	ŌĒAB	'A' to 'B' output enable input (active LOW)
14	TEAB	'A' to 'B' latch enable input (active LOW)
23	ĒAB	'A' to 'B' enable input (active LOW)
24	VCC	Positive supply voltage

PIN	CONFIGURATION

LEBA 1	24 V _{CC}
OEBA 2	23 EBA
A0 3	22 BO
A1 4	21 B1
A2 5	20 B2
A3 6	19 B3
Ā4 7	18 B4
A5 8	17 B5
A6 9	16 B6
A7 10	15 B7
EAB 11	14 LEAB
GND 12	13 OEAB
	SV00733

FUNCTION TABLE

	INPU	JTS		OUTPUTS	STATUS
OEXX	ĒXX	LEXX	DATA	0017013	STATUS
Н	Х	Х	Х	Z	Disabled
Х	Н	Х	Х	Z	Disabled
L	$\uparrow \\ \uparrow$	L	h I	Z Z	Disabled + Latch
L	L L	$\uparrow \uparrow$	h I	L H	Latch + Display
L	L L	L	H L	L H	Transparent
L	L	Н	Х	NC	Hold

= AB for A-to-B direction, BA for B-to-A direction = HIGH voltage level XX H

L = LOW voltage level

= HIGH state must be present one set-up time before the LOW-to-HIGH transition of LEAB, LEBA, EAB, EBA = LOW state must be present one set-up time before the LOW-to-HIGH transition of LEAB, LEBA, EAB, EBA h L

X ↑ = Don't care

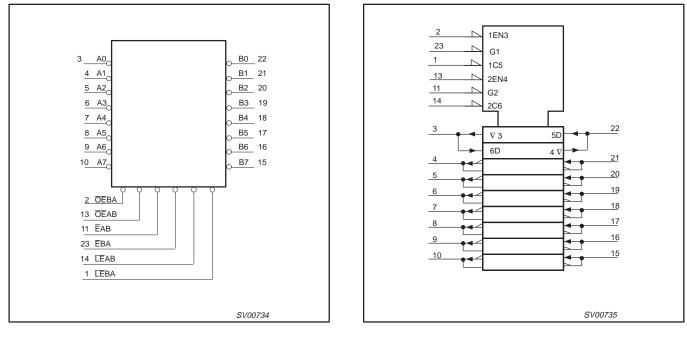
= LOW-to-HIGH level transition

NC = No change

= High impedance OFF-state Ζ

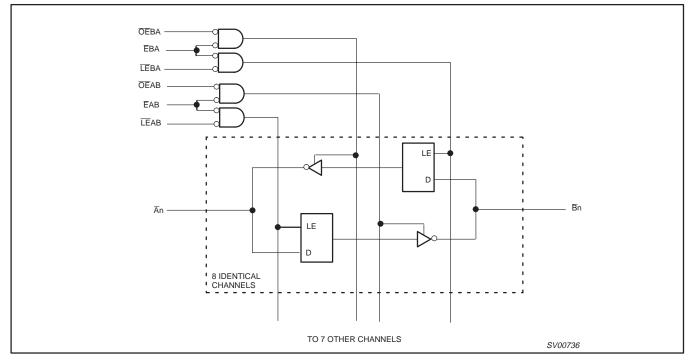
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LOGIC SYMBOL



LOGIC SYMBOL (IEEE/IEC)

LOGIC DIAGRAM



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74LVC544A

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	CONDITIONS	LIMITS		UNIT
OTIMBOL	FARAMETER	CONDITIONS	MAX		
Vcc	DC supply voltage (for max. speed performance)		2.7	3.6	V
VCC	DC supply voltage (for low-voltage applications)		1.2	3.6	v
VI	DC input voltage range		0	5.5	V
V.	DC output voltage range; output HIGH or LOW state		0	V _{CC}	V
Vo	DC output voltage range; output 3-State		0	5.5	v
T _{amb}	Operating free-air temperature range		-40	+85	°C
t _r , t _f	Input rise and fall times	V _{CC} = 1.2 to 2.7V V _{CC} = 2.7 to 3.6V	0 0	20 10	ns/V

ABSOLUTE MAXIMUM RATINGS¹

In accordance with the Absolute Maximum Rating System (IEC 134) Voltages are referenced to GND (ground = 0V)

SYMBOL	PARAMETER	CONDITIONS	RATING	UNIT
V _{CC}	DC supply voltage		-0.5 to +6.5	V
I _{IK}	DC input diode current	V ₁ < 0	-50	mA
VI	DC input voltage	Note 2	-0.5 to +6.5	V
I _{OK}	DC output diode current	$V_{O} > V_{CC} \text{ or } V_{O} < 0$	±50	mA
M	DC output voltage; output HIGH or LOW	Note 2	–0.5 to V _{CC} +0.5	V
Vo	DC output voltage; output 3-State	Note 2	-0.5 to 6.5	V
Ι _Ο	DC output source or sink current	$V_{O} = 0$ to V_{CC}	±50	mA
I _{GND} , I _{CC}	DC V _{CC} or GND current		±100	mA
T _{stg}	Storage temperature range		-65 to +150	°C
P _{TOT}	Power dissipation per package – plastic mini-pack (SO) – plastic shrink mini-pack (SSOP and TSSOP)	above +70°C derate linearly with 8 mW/K above +60°C derate linearly with 5.5 mW/K	500 500	mW

NOTES:

1. Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

2. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

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DC ELECTRICAL CHARACTERISTICS

Over recommended operating conditions voltages are referenced to GND (ground = 0V)

		LIMITS		IMITS		
SYMBOL	PARAMETER	TEST CONDITIONS	Temp = -40°C to +85°C			
			MIN	TYP ¹	МАХ	1
V		V _{CC} = 1.2V	V _{CC}			v
V _{IH}	HIGH level Input voltage	V _{CC} = 2.7 to 3.6V	2.0			
M		$V_{CC} = 1.2V$			GND	v
V _{IL}	LOW level Input voltage	V _{CC} = 2.7 to 3.6V			0.8	
		V_{CC} = 2.7V; V_I = V_{IH} or V_{IL} ; I_O = -12mA	$V_{CC} - 0.5$			
V		V_{CC} = 3.0V; V_I = V_{IH} or V_{IL} ; I_O = -100 μ A	$V_{CC} - 0.2$	V _{CC}		V
V _{OH}	HIGH level output voltage	V_{CC} = 3.0V; V_I = V_{IH} or V_{IL} ; I_O = -18mA	$V_{CC} - 0.6$			
		V_{CC} = 3.0V; V_I = V_{IH} or V_{IL} ; I_O = -24mA	$V_{CC} - 0.8$			
		V_{CC} = 2.7V; V_{I} = V_{IH} or V_{IL} ; I_{O} = 12mA			0.40	
V _{OL}	LOW level output voltage	$V_{CC} = 3.0V; V_I = V_{IH} \text{ or } V_{IL}; I_O = 100 \mu A$		GND	0.20	V
		V_{CC} = 3.0V; V_I = V_{IH} or V_{IL} ; I_O = 24mA			0.55	
II.	Input leakage current	$V_{CC} = 3.6V; V_{I} = 5.5V \text{ or GND}$		±0.1	±5	μA
I _{OZ}	3-State output OFF-state current	$V_{CC} = 3.6V; V_I = V_{IH} \text{ or } V_{IL}; V_O = 5.5V \text{ or GND}$		0.1	±5	μA
I _{OFF}	Power off leakage current	$V_{CC} = 0.0V; V_I = 5.5V; V_O = 5.5V$		0.1	±10	μA
I _{CC}	Quiescent supply current	$V_{CC} = 3.6V; V_I = V_{CC} \text{ or GND}; I_O = 0$		0.1	10	μΑ
ΔI_{CC}	Additional quiescent supply current per input pin	$V_{CC} = 2.7V$ to 3.6V; $V_I = V_{CC} - 0.6V$; $I_O = 0$		5	500	μA

NOTES:

1. All typical values are at V_{CC} = 3.3V and T_{amb} = 25°C.

AC CHARACTERISTICS

GND = 0 V; t_r = t_f $\leq~$ 2.5 ns; CL = 50 pF

					LIMITS			
SYMBOL	PARAMETER	WAVEFORM	Vc	_C = 3.3V ±0	.3V	V _{CC} =	= 2.7V	UNIT
			MIN	TYP ¹	MAX	MIN	MAX	
t _{PHL} /t _{PLH}	Propagation delay An to Bn, Bn to An	Figures 1, 5	1.5	4	6.5	1.5	7.5	ns
t _{PHL} /t _{PLH}	Propagation delay LEBA to An, LEAB to Bn	Figures 2, 5	1.5	4.3	7.5	1.5	8.5	ns
t _{PZH} /t _{PZL}	3-State output enable time OEBA to An, OEAB to Bn	Figures 3, 5	1.5	4.5	8.5	1.5	9.5	ns
t _{PHZ} /t _{PLZ}	3-State output disable time OEBA to An, OEAB to Bn	Figures 3, 5	1.5	3.9	6.5	1.5	7.5	ns
t _{PZH} /t _{PZL}	3-State output enable time EBA to An, EAB to Bn	Figures 3, 5	1.5	4.7	8.9	1.5	9.9	ns
t _{PHZ} /t _{PLZ}	3-State output disable time EBA to An, EAB to Bn	Figures 3, 5	1.5	3.9	6.9	1.5	7.9	ns
t _W	LEXX pulse width HIGH	Figure 2	2.0	-	-	2.0	-	ns
t _{su}	Set-up time An/Bn to LEXX, An/Bn to EXX	Figure 4	2.0	_	_	2.0	_	ns
t _h	Hold time Ān/Bn to LEXX, Ān/Bn to EXX	Figure 4	4.0	-	-	1.0	-	ns

NOTE:

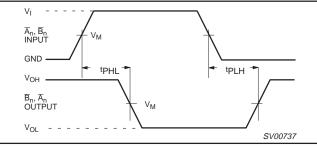
1. These typical values are at V_{CC} = 3.3V and T_{amb} = 25°C.

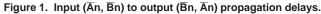
74LVC544A

AC WAVEFORMS

 $\begin{array}{l} \mathsf{V}_{\mathsf{M}} = 1.5\mathsf{V} \mbox{ at } \mathsf{V}_{\mathsf{CC}} \geq 2.7\mathsf{V} \\ \mathsf{V}_{\mathsf{M}} = 0.5\mathsf{V}^* \ \mathsf{V}_{\mathsf{CC}} \mbox{ at } \mathsf{V}_{\mathsf{CC}} < 2.7\mathsf{V} \\ \mathsf{V}_{\mathsf{OL}} \mbox{ and } \mathsf{V}_{\mathsf{OH}} \mbox{ are the typical output voltage drop that occur with the output load.} \\ \mathsf{V}_{\mathsf{X}} = \mathsf{V}_{\mathsf{OL}} + 0.3\mathsf{V} \mbox{ at } \mathsf{V}_{\mathsf{CC}} \geq 2.7\mathsf{V} \\ \mathsf{V}_{\mathsf{X}} = \mathsf{V}_{\mathsf{OL}} + 0.1\mathsf{V}_{\mathsf{CC}} \mbox{ at } \mathsf{V}_{\mathsf{CC}} < 2.7\mathsf{V} \\ \mathsf{V}_{\mathsf{Y}} = \mathsf{V}_{\mathsf{OH}} - 0.3\mathsf{V} \mbox{ at } \mathsf{V}_{\mathsf{CC}} \geq 2.7\mathsf{V} \end{array}$

 $V_{Y} = V_{OH} - 0.1 V_{CC}$ at $V_{CC} < 2.7 V$





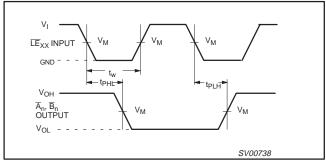


Figure 2. Latch enable input (LEXX) pulse width, the latch enable input to output (Ān, Bn) propagation delays.

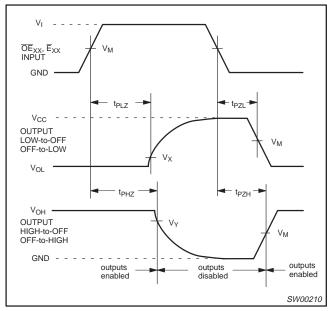


Figure 3. 3-State enable and disable times

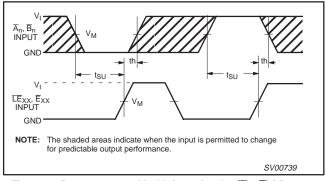


Figure 4. Data set-up and hold times for the (\overline{An} , \overline{Bn}) input to the $\overline{LE}XX$ and $\overline{E}XX$ inputs

TEST CIRCUIT

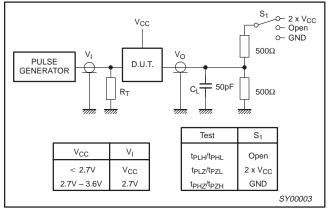
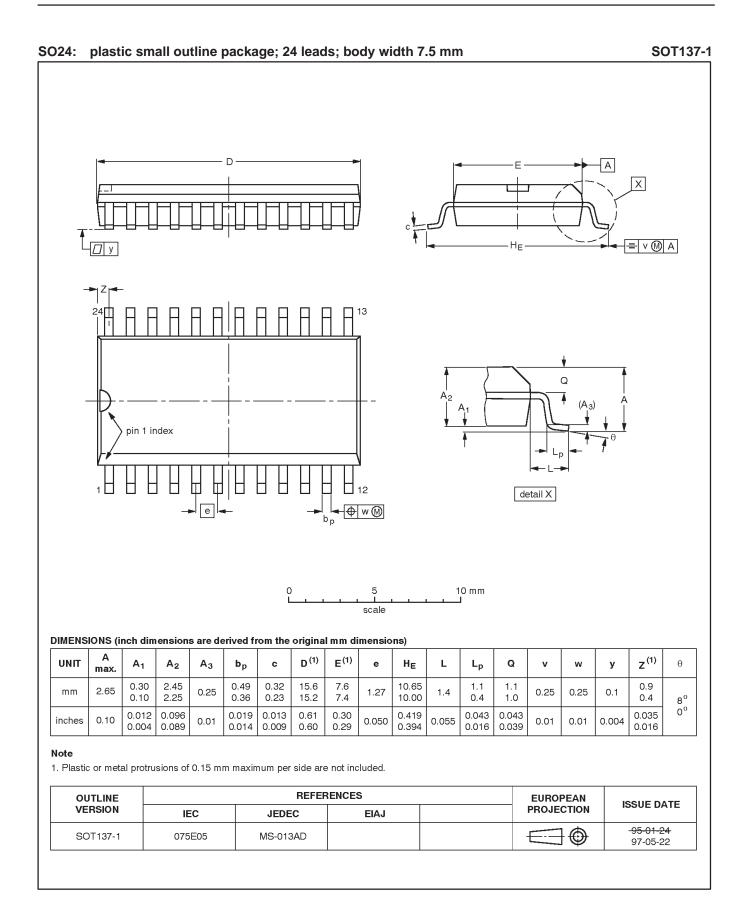
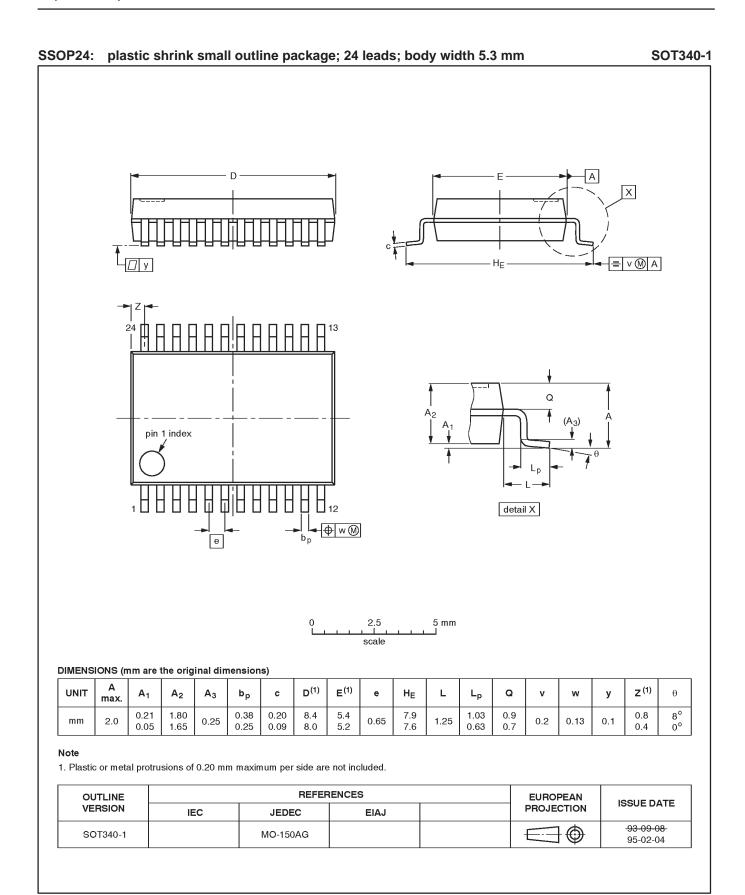


Figure 5. Load circuitry for switching times

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74LVC544A



74LVC544A

Data sheet status

Data sheet status	Product status	Definition ^[1]
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.
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Product specification	Production	This data sheet contains final specifications. Philips Semiconductors reserves the right to make changes at any time without notice in order to improve design and supply the best possible product.

[1] Please consult the most recently issued datasheet before initiating or completing a design.

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Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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